



# Certificate of Presentation

We hereby certify that the work  
**Experimental Analysis of Negative Temperature Bias Instabilities Degradation  
in Junctionless Nanowire Transistors**

by

**Nilton Graziano Junior, Fernando José da Costa, Renan Trevisoli and  
Rodrigo Trevisoli Doria**

was presented at the XIV Workshop on Semiconductors and Micro & Nano  
Technology, in Campinas-SP, held on April 11-12, 2019.

A handwritten signature in blue ink, which appears to read "Jacobus Swart".

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Dr. Jacobus Swart  
SEMINATEC 2019 General Chair